

TIC226A, TIC226B, TIC226C, TIC226D, TIC226E, TIC226M, TIC226N, TIC226S

SILICON BIDIRECTIONAL TRIODE THYRISTOR

- 8 A RMS
- 70 A Peak
- · Glass Passivated Wafer
- 100 V to 800 V Off-State Voltage
- Max I_{GT} of 50 mA (Quadrants 1-3)
- High-temperature, High-current and high-voltage applications
- Compliance to ROHS

DESCRIPTION

This device is a bidirectional triode thyristor (triac) which may be triggered from the off-state to the onstate by either polarity of gate signal with main Terminal 2 at either polarity.

ABSOLUTE MAXIMUM RATINGS

Symbol	Ratings	Value							Unit	
- ,		Α	В	С	D	Е	M	s	N	
V _{DRM}	Repetitive peak off-state voltage (see Note1)	100	200	300	400	500	600	700	800	V
I _{T(RMS)}	Full-cycle RMS on-state current at (or below) 70°C case temperature (see note2)	8					Α			
I _{TSM}	Peak on-state surge current full-sine-wave (see Note3)	70					Α			
I _{TSM}	Peak on-state surge current half-sine-wave (see Note4)	8					Α			
I _{GM}	Peak gate current	± 1							Α	
P _{GM}	Peak gate power dissipation at (or below) 85°C case temperature (pulse width ≤200 µs)				W					
P _{G(AV)}	Average gate power dissipation at (or below) 85°C case (see Note5)	0.9				W				
T _C	Operating case temperature range -40 to +110				°C					
T _{stg}	Storage temperature range -40 to +125				°C					
TL	Lead temperature 1.6 mm from case for 10 seconds				°C					



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THERMAL CHARACTERISTICS

Symbol	Ratings	Value	Unit		
R _{∂JC}	Junction to case thermal resistance	≤ 1.8	°C/W		
R _{∂JA}	Junction to free air thermal resistance	≤ 62.5	C/VV		

ELECTRICAL CHARACTERISTICS

TC=25°C unless otherwise noted

Symbol	Ratings	Test Condition(s)	Min	Тур	Max	Unit	
I _{DRM}	Repetitive peak off-state current	V_D = Rated V_{DRM} , , I_G = 0 T_C = 110°C	-	-	±2	mA	
I _{GT}	Gate trigger current	$V_{\text{supply}} = +12 \text{ V}^{+}, R_{\text{L}} = 10 \Omega, t_{\text{p(g)}} = > 20 \mu\text{s}$	-	2	50	mA	
		$V_{\text{supply}} = +12 \text{ V}^{\dagger}, R_{\text{L}} = 10 \Omega, t_{\text{p(g)}} = > 20 \mu\text{s}$	-	-12	-50		
		$V_{\text{supply}} = -12 \text{ V}^{\dagger}, R_L = 10 \Omega, t_{p(g)} = > 20 \mu \text{s}$	-	-9	-50		
		$V_{\text{supply}} = -12 \text{ V}^{\dagger}, R_{\text{L}} = 10 \Omega, t_{\text{p(g)}} = > 20 \mu\text{s}$	-	20	-		
V_{GT}		$V_{\text{supply}} = +12 \text{ V}^{\dagger}, R_{\text{L}} = 10 \Omega, t_{\text{p(g)}} = > 20 \mu \text{s}$	-	0.7	2	V	
	Gate trigger voltage	V_{supply} = +12 V†, R_L = 10 Ω , $t_{p(g)}$ = > 20 μ s	-	-0.8	-2		
		$V_{\text{supply}} = -12 \text{ V}^{\dagger}, R_L = 10 \Omega, t_{p(g)} = > 20 \mu \text{s}$	-	-0.8	-2		
		$V_{\text{supply}} = -12 \text{ V}^{\dagger}, R_L = 10 \Omega, t_{p(g)} = > 20 \mu \text{s}$	-	0.9	2		
I _H	Holding current	V_{supply} = +12 V†, I_{G} = 0 initiating I_{TM} = 100 mA	-	5	30	mΛ	
		$V_{\text{supply}} = -12 \text{ V}^{\dagger}, I_{\text{G}} = 0$ initiating $I_{\text{TM}} = -100 \text{ mA}$	-	-9	-30	mA	
ı	Latching current	V _{supply} = +12 V† (seeNote7)	50		50	mΛ	
IL	Latching current $\frac{V_{\text{supply}}}{V_{\text{supply}}} = -12 \text{ V}^{+} \text{ (seeNote7)}$		-	-	-50	mA	
V _{TM}	Peak on-state voltage	$I_{TM} = \pm 12 \text{ A}, I_G = 50 \text{ mA (see Note6)}$	-	±1.6	±2.1	V	
dv/dt	Critical rate of rise of off-state voltage	V_{DRM} = Rated V_{DRM} , I_G = 0 T_C = 110°C	-	±100 -			
dv/dt⊚	Critical rise of communication voltage	V_{DRM} = Rated V_{DRM} , I_{TRM} = ± 12A T_C = 85°C	±5	-	-	V/µs	

[†] All voltages are whit respect to Main Terminal 1.



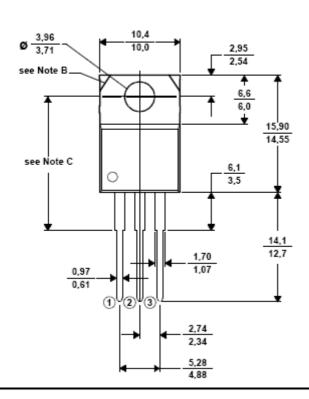
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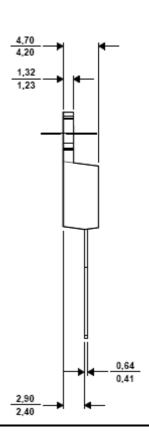
Notes:

- 1. These values apply bidirectionally for any value of resistance between the gate and Main
- 2. This value applies for 50-Hz full-sine-wave operation with resistive load. Above 85°C derate linearly to 110°C case temperature at the rate of 320 mA/°C.
- 3. This value applies for one 50-Hz full-sine-wave when the device is operating at (or below) the rated value of on-state current. Surge may be repeated after the device has returned to original thermal equilibrium. During the surge, gate control may be lost.
- 4. This value applies for one 50-Hz half-sine-wave when the device is operating at (or below) the rated value of on-state current. Surge may be repeated after the device has returned to original thermal equilibrium. During the surge, gate control may be lost.
- 5. This value applies for a maximum averaging time of 20 ms.
 6. This parameters must be measured using pulse techniques, t_W = ≤1ms, duty cycle ≤ 2 %, voltage-sensing contacts, separate from the courrent-carrying contacts are located within 3.2mm (1/8 inch) from de device body.
- 7. The triacs are triggered by a 15-V (open circuit amplitude) pulse supplied by a generator with the following characteristics : $R_G = 100\Omega$, $t_{p(q)} = 20 \mu s$, $t_r = \le 15 ns$, f = 1 kHz.

MECHANICAL DATA CASE TO-220



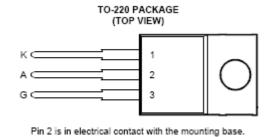






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PINNING



Pin 1 :	kathode
Pin 2:	Anode
Pin 3 :	Gate

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